



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/803,264
Filing Date March 17, 2004
Inventor..... Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Group Art Unit..... 2829
Examiner Russell M. Kobert
Attorney's Docket No. MI22-2524
Customer No.. 021567
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

RESPONSE TO JANUARY 31, 2006 FINAL OFFICE ACTION
PURSUANT TO 37 C.F.R. §1.116

To: Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: D. Brent Kenady
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Responsive to the January 31, 2006 Final Office Action, Applicant amends and
remarks as follows:

AMENDMENTS

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.

07/05/2006 RMEBRAHT 00000024 10803264

01 FC:1252
02 FC:1201
03 FC:1202

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200.00 OP
50.00 OP

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